

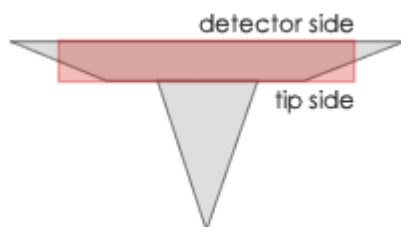
Cantilever Data	Value	Range*
Resonance Frequency	160 kHz	120 - 205 kHz
Force Constant	7.4 N/m	3 - 16 N/m
Length	150 μm	145 - 155 μm
Mean Width	27 μm	22 - 32 μm
Thickness	2.8 μm	2.3 - 3.3 μm

NanoWorld® Pointprobe® NCST AFM probes are designed for non-contact or soft tapping mode imaging. The combination of soft AFM cantilever and fairly high resonance frequency enables stable and fast measurements with reduced AFM tip-sample interaction. Thus, AFM tip and sample wear could be significantly decreased.

All SPM and AFM probes of the Pointprobe® series are made from monolithic silicon which is highly doped to dissipate static charge. They are chemically inert and offer a high mechanical Q-factor for high sensitivity. The AFM tip is shaped like a polygon based pyramid with a typical height of 10 - 15 μm .

Additionally, this AFM probe offers a typical AFM tip radius of curvature of less than 8 nm.

For applications requiring lower resonance frequencies or an AFM cantilever length exceeding 150 μm we recommend our Pointprobe® type [NCL](#). For standard non-contact / tapping mode application we recommend our Pointprobe® type [NCH](#).



A trapezoidal cross section of the AFM cantilever and therefore 30% wider (e.g. NCH) AFM cantilever detector side result in easier and faster laser adjustment. Additionally, because there is simply more space to place and reflect the laser beam, a higher SUM signal is reached.

Tip shape: Standard
Coating: none

Order Code	Quantity	Data Sheet
NCST-10	10	yes
NCST-20	20	yes
NCST-50	50	no
NCST-W	380	yes